

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10553977	YANO ET AL.
	Examiner BRYAN T KILPATRICK	Art Unit 1797

SEARCHED

Class	Subclass	Date	Examiner
356		02/02/2009	BK
422	82.01	02/02/2009	BK

SEARCH NOTES

Search Notes	Date	Examiner
Internet search	03/11/2009	BK
EAST search	03/11/2009	BK
((KOJI) near2 (YANO)).INV.	03/11/2009	BK
((TAKESHI) near2 (IMAMURA)).INV.	03/11/2009	BK
((MITSURO) near2 (SUGITA)).INV.	03/11/2009	BK
((KOHEI) near2 (OKAMOTO)).INV.	03/11/2009	BK
((TAKEO) near2 (YAMAZAKI)).INV.	03/11/2009	BK
((HIDENORI) near2 (SHIOTSUKA)).INV.	03/11/2009	BK
((TOSHIHIKO) near2 (OUCHI)).INV.	03/11/2009	BK
((RYO) near2 (KURODA)).INV.	03/11/2009	BK
(detect\$3 and electromagnetic near3 wave and substance or sample).clm.	03/11/2009	BK
(target near3 (substance\$1 or molecule\$1 or sample\$1)) and ((passing or moving) near3 fluid) and (structure\$1 or wall\$1) and detect\$3 and (electromagnetic near3 wave\$1) and (substance\$1 or sample\$1) and wave\$1 and (emitt\$3 or emmission\$1) and refract\$4 and sensor\$1 and (bind\$3 or bond\$3)	03/11/2009	BK
two\$1division adj (detector\$1 or sensor\$1)	09/08/2010	BK
and sample\$1	09/08/2010	BK

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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